



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **YAMAGISHI, Yasuo, et al.**

Group Art Unit: **2829**

Serial No.: **10/621,445**

Examiner: **HOLLINGTON, Jermele M.**

Filed: **July 18, 2003**

P.T.O. Confirmation No.: 1112

**FOR: PROBE CARD AND TESTING METHOD OF SEMICONDUCTOR CHIP,
CAPACITOR AND MANUFACTURING METHOD THEREOF**

AMENDMENT UNDER 37 CFR §1.111

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

May 10, 2005

Sir:

In response to the Office Action dated **January 10, 2005**, extended to **May 10, 2005** by a **one (1) month** Petition for Extension of Time, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 11 of this paper.